

**In the United States Patent and Trademark Office**

In re the application of  
Lee D. Whetsel

TI-28085.2

Application No. 10/771,768

Art Unit: 2138  
Conf. No. 5155

Filed: 2/2/2004

Examiner: Phung M. Chung

Title: Low Power Testing of Very Large Circuits

**Amendment B Under 37 CFR 1.111**

August 4, 2006

Asst. Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313

Dear Sir:

Responsive to the Examiner's Action of 05/05/2006, please  
amend this application as follows: